## Search Notes



Application/Control No.	Applicant(s)/Patent Under Reexamination
10661322	PARIDA ET AL.
Examiner	Art Unit
PETER COUGHLAN	2129

SEARCHED					
Class	Subclass	Date	Examiner		
706	@pd<20030905 and 12, 13, 15	11/29/2007	PDC		
706	@ad<20030905 and @pd>20071129 and 20, 15, 16, 12, 13	5/30/2008	PDC		
706	@pd<20030905 w/ permutation, pattern and 45, 46, 25, 26	11/24/2008	PDC		
707	@pd<20030905 w/permutation , pattern and 100	11/24/2008	PDC		

SEARCH NOTES				
Search Notes	Date	Examiner		
East @pd<20030905 and permutation pattern, detection, balanced tree, IBM, offset, selecting, memory, substring, value, input string, characters, amino acids, genome, permutation, curve fitting, degree polynomial, binary tree	11/29/2007	PDC		
IEEE <2008 and Laxmi Parida, Revital Erez, Menachem Landau, Pattern detection, permutations, window, string, balanced search tree, IBM, substring, amino acids, genome, curve fitting, degree polynomial, binary tree	11/29/2007	PDC		
Dogpile permutation patterns, detection, balanced trees, IBM, offset, selecting, memory, substring, value, input string,	11/29/2007	PDC		
Inventors and Laxmi Parida, Revital Erez, Menachem Landau,	11/29/2007	PDC		
East — @ad<20030905 and @pd>20071129 and permutation, pattern, input string, character, colocale, co locate, co-locate, relationship, between, group, shift input, string, window	5/30/2008	PDC		
IEEE <2004 and @pd>20071129 and permutation, pattern, input string, character, colocale, co locate, co-locate, relationship, between, group, shift input, string, window	11/24/2008	PDC		

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

U.S. Patent and Trademark Office Part of Paper No.: 11252008A